

Title (en)  
Semiconductor integrated circuit

Title (de)  
Integrierte Halbleiterschaltung

Title (fr)  
Circuit intégré à semi-conducteur

Publication  
**EP 0489394 B1 19970716 (EN)**

Application  
**EP 91120719 A 19911203**

Priority  
JP 40058490 A 19901206

Abstract (en)  
[origin: EP0489394A2] A semiconductor integrated circuit having a test circuit built therein is disclosed which comprises an A/D converter to be connected to an peripheral circuit, a digital circuit connected to the A/D converter, a digital signal switching device for connecting the output of the A/D converter and that of the digital circuit selectively and a boundary scan output circuit connected to the output of the digital signal switching device connects the A/D converter to the boundary scan output circuit in a normal mode and the signal fetched in the boundary scan output circuit are outputted therefrom in test mode. Semiconductor integrated circuits having an analog circuit built therein and an analog integrated circuit in which a test circuit is built-in are also disclosed. <IMAGE>

IPC 1-7  
**G06F 11/22**; **G06F 11/26**

IPC 8 full level  
**G06F 3/05** (2006.01); **G01R 31/3167** (2006.01); **G01R 31/3185** (2006.01); **H03M 1/12** (2006.01)

CPC (source: EP KR US)  
**G01R 31/3167** (2013.01 - EP US); **G01R 31/318536** (2013.01 - EP US); **H03M 1/12** (2013.01 - KR)

Cited by  
CN111045405A; CN109642925A; EP0933644A1; US5581176A; US5705925A; US6327683B1; WO2005006005A1

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